

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
H0004116-USSERIAL NO.
10/614,807LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Wuwen Yi et al.FILING DATE
July 9, 2003GROUP
1742

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	2002/0041819 A1	04/02	Kumar et al.			
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AF							
	AG							
	AH							
	AI							
	AJ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

HW	AK		V. Pavate et al., Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect density, pp. 42-47, SPIE Vol. 3214, 1997
	AL		
EXAMINER <i>/Harry Wilkins/</i>		DATE CONSIDERED	04/24/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	6,192,969	02/01	Bunn et al.			
HW	AB	6,569,270 B2	05/03	Segal			
HW	AC	2003/005200A1 <u>2003/005200A1</u>	03/03	Segal et al.			
	AD						
	AE						
	AF						
	AG						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AH						
	AI						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AJ		C.A. Michaluk, et al. <i>Methodologies for Determining the Global Texture of Tantalum Plate Using X-Ray Diffraction</i> , The Minerals, Metals & Materials Society, pps. 123-131, 1996.				
	AK						
EXAMINER <u>/Harry Wilkins</u>		DATE CONSIDERED <u>04/24/2006</u>					
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